

# VLSI Technology (4353206) - Summer 2025 Solution

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## Question 1(a) [3 marks]

Draw neat labeled diagram of physical structure of n-channel MOSFET.

### Solution

#### Physical Structure of n-channel MOSFET:

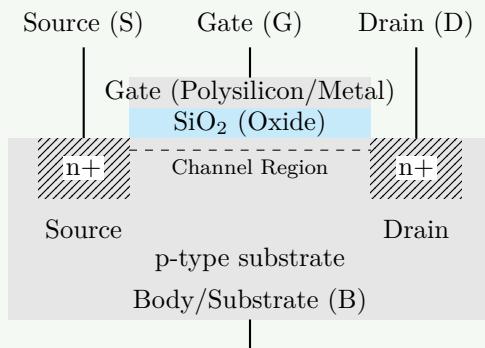


Figure 1. n-channel MOSFET Structure

#### Key Components:

- **Source:** n+ doped region providing electrons
- **Drain:** n+ doped region collecting electrons
- **Gate:** Metal electrode controlling channel
- **Oxide:** SiO<sub>2</sub> insulating layer
- **Substrate:** p-type silicon body

### Mnemonic

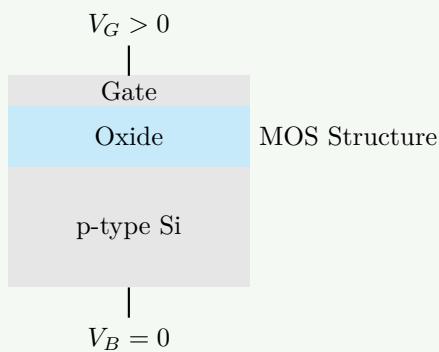
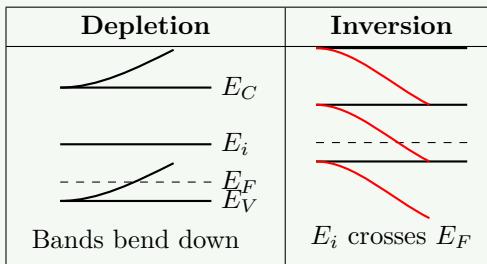
“SOGD - Source, Oxide, Gate, Drain”

## Question 1(b) [4 marks]

Draw energy band diagram of depletion and inversion of MOS under external bias with MOS biasing diagram. Explain inversion region in detail.

### Solution

#### MOS Biasing Circuit:

**Figure 2.** MOS Biasing**Energy Band Diagrams:****Inversion Region Details:**

- **Strong inversion:**  $V_G > V_T$  (threshold voltage)
- **Electron channel:** Forms at Si-SiO<sub>2</sub> interface as minority carriers (electrons) accumulate.
- **Channel conductivity:** Increases with gate voltage.
- **Threshold condition:** Surface potential  $\phi_s = 2\phi_F$ .

**Mnemonic**

“DIVE - Depletion, Inversion, Voltage, Electrons”

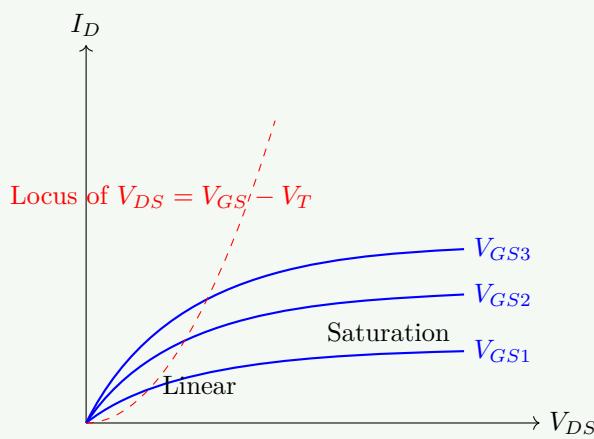
**Question 1(c) [7 marks]**

Explain I-V characteristics of MOSFET.

**Solution****I-V Characteristic Regions:****Table 1.** Operating Regions

Region	Condition	Drain Current ( $I_D$ )
<b>Cutoff</b>	$V_{GS} < V_T$	$I_D \approx 0$
<b>Linear</b>	$V_{GS} > V_T, V_{DS} < V_{GS} - V_T$	$I_D = \mu_n C_{ox} \frac{W}{L} [(V_{GS} - V_T)V_{DS} - \frac{V_{DS}^2}{2}]$
<b>Saturation</b>	$V_{GS} > V_T, V_{DS} \geq V_{GS} - V_T$	$I_D = \frac{1}{2} \mu_n C_{ox} \frac{W}{L} (V_{GS} - V_T)^2$

**Characteristic Curve:**

**Figure 3.** MOSFET I-V Characteristics**Key Parameters:**

- $\mu_n$ : Electron mobility
- $C_{ox}$ : Gate oxide capacitance per unit area
- $W/L$ : Channel Width to Length ratio
- $V_T$ : Threshold voltage

**Mnemonic**

“CLS - Cutoff, Linear, Saturation”

**Question 1(c) OR [7 marks]**

Define scaling. Explain the need of scaling. List and explain the negative effects of scaling.

**Solution**

**Definition:** Scaling is the systematic reduction of MOSFET dimensions to improve performance and density.

**Need for Scaling:**

- **Higher Density:** More transistors per chip area, following Moore’s Law.
- **Faster Speed:** Reduced channel length reduces carrier transit time ( $t = L^2/\mu V$ ).
- **Lower Power:** Smaller parasitic capacitances decrease switching energy.
- **Cost Reduction:** More chips per wafer reduces cost per die.

**Scaling Types:****Table 2.** Scaling Strategies

Type	Gate Length	Supply Voltage	Oxide Thickness
Constant Voltage	$\downarrow \alpha$	Constant	$\downarrow \alpha$
Constant Field	$\downarrow \alpha$	$\downarrow \alpha$	$\downarrow \alpha$

**Negative Effects:**

- **Short Channel Effects (SCE):**  $V_T$  roll-off and drain-induced barrier lowering (DIBL).
- **Hot Carrier Effects:** High electric fields near drain inject carriers into oxide, degrading device.
- **Gate Leakage:** Thin oxide leads to quantum tunneling current.
- **Process Variations:** Difficulty in controlling dimensions at nano-scale.
- **Power Density:** Increased heat per unit area creates thermal management issues.

**Mnemonic**

“SHGPP - Short channel, Hot carrier, Gate leakage, Process, Power”

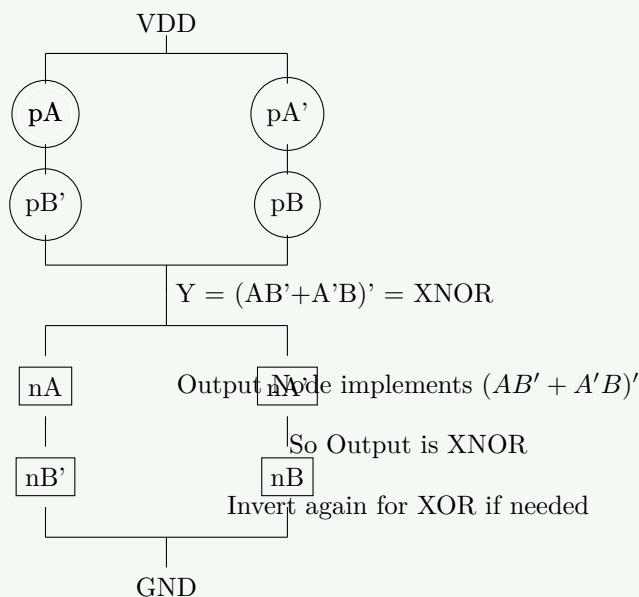
**Question 2(a) [3 marks]**

Implement  $Y' = (AB' + A'B)$  using CMOS.

**Solution**

**Logic Analysis:**  $Y' = AB' + A'B = A \oplus B$  (XOR function).

**CMOS Implementation:**



**Figure 4.** Static CMOS Implementation for XNOR (inverted XOR)

*Note: The circuit above implements  $(AB' + A'B)'$ . To get  $Y' = AB' + A'B$ , we technically need an inverter at the output, or this represents the structure where pull-down matches the expression.*

**Mnemonic**

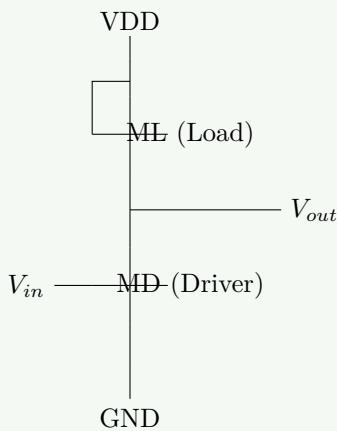
“XOR needs complementary switching”

**Question 2(b) [4 marks]**

Explain enhancement load inverter with its circuit diagrams.

**Solution**

**Circuit Diagram:**

**Figure 5.** Saturated Enhancement Load Inverter**Configuration:**

- **Load (ML):** Enhancement NMOS with Gate connected to Drain ( $V_{GS} = V_{DS}$ ). Always in Saturation or Cutoff.
- **Driver (MD):** Enhancement NMOS with Gate as input.

**Operation:**

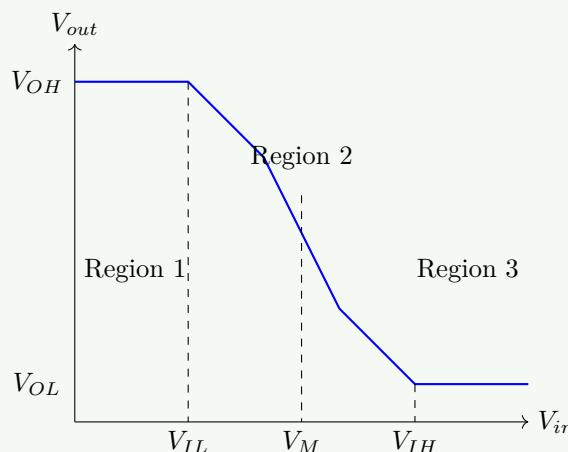
- **High Output ( $V_{OH}$ ):** Limited to  $V_{DD} - V_T$  because load turns off when  $V_{out}$  rises to that level.
- **Low Output ( $V_{OL}$ ):** Close to 0V (depends on ratio  $K_D/K_L$ ).
- **Disadvantage:** Degraded logic high ( $V_{DD} - V_T$ ) and continuous power dissipation when  $V_{in}$  is high.

**Mnemonic**

“ELI - Enhancement Load Inverter has threshold Issues”

**Question 2(c) [7 marks]**

Explain Voltage Transfer Characteristic of inverter.

**Solution****VTC Curve:****Figure 6.** Ideally Inverter VTC**Key Parameters:**

Parameter	Description	Ideal Value
$V_{OH}$	Output High Voltage	$V_{DD}$
$V_{OL}$	Output Low Voltage	0V
$V_{IH}$	Input High Voltage	$\approx V_{DD}/2$
$V_{IL}$	Input Low Voltage	$\approx V_{DD}/2$
$V_M$	Switching Threshold	$V_{DD}/2$

**Noise Margins:**

- $NM_H = V_{OH} - V_{IH}$  (High noise margin)
- $NM_L = V_{IL} - V_{OL}$  (Low noise margin)

**Regions:**

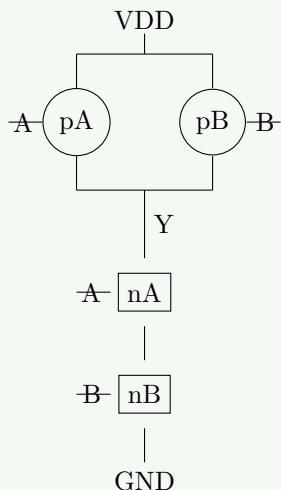
- Region 1:**  $V_{in}$  low,  $V_{out}$  high (PMOS Linear, NMOS Cutoff)
- Region 2:** Transition region (Both Saturation)
- Region 3:**  $V_{in}$  high,  $V_{out}$  low (PMOS Saturation, NMOS Linear)

**Mnemonic**

“VTC shows VOICE - VOH, VOL, Input thresholds, Characteristics, Everything”

**Question 2(a) OR [3 marks]**

Explain NAND2 gate using CMOS.

**Solution****CMOS NAND2 Circuit:**

**Figure 7.** CMOS NAND2 Gate

**Operation:**

- Pull-Up Network:** PMOS inputs A and B in parallel. If A=0 OR B=0, output pulled to VDD.
- Pull-Down Network:** NMOS inputs A and B in series. Only if A=1 AND B=1, output pulled to GND.

**Truth Table:**

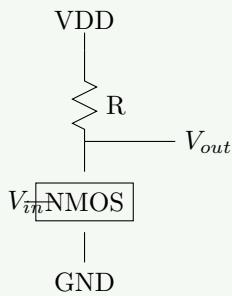
A	B	Y
0	0	1
0	1	1
1	0	1
1	1	0

**Mnemonic**

“NAND - Not AND, Parallel PMOS, Series NMOS”

**Question 2(b) OR [4 marks]**

Explain operating mode and VTC of Resistive load inverter circuit.

**Solution****Circuit Configuration:**

**Figure 8.** Resistive Load Inverter

**Operating Modes:**

- $V_{in} = 0$  (**Low**): NMOS OFF.  $V_{out} = V_{DD}$ .
- $V_{in} = V_{DD}$  (**High**): NMOS ON (Linear).  $V_{out} = V_{VOL}$ .
- **$V_{OL}$  Calculation:**  $V_{OL} = \frac{R_{ON}}{R_{ON}+R} V_{DD}$ .

**Design Trade-offs:**

- **Large R:** Better  $V_{OL}$ , lower power, but slower switching (high RC delay).
- **Small R:** Faster switching, but poor  $V_{OL}$  and high power consumption.
- **Area:** Resistors consume significant silicon area compared to transistors.

**Mnemonic**

“RLI - Resistive Load has Inevitable power consumption”

**Question 2(c) OR [7 marks]**

Draw CMOS inverter and explain its operation with VTC.

**Solution****CMOS Inverter Circuit:**

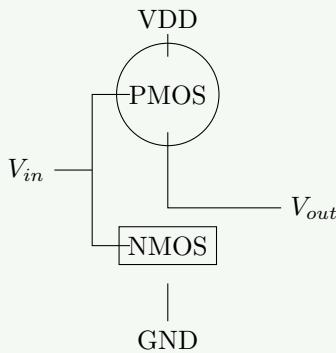


Figure 9. CMOS Inverter

**Operation Regions:**

$V_{in}$ Range	PMOS	NMOS	$V_{out}$	Region
0 to $V_{TN}$	ON	OFF	$V_{DD}$	1
$V_{TN}$ to $V_{DD} -  V_{TP} $	ON	ON	Transition	2
$V_{DD} -  V_{TP} $ to $V_{DD}$	OFF	ON	0V	3

**VTC Analysis:** The VTC is nearly ideal square-like.

- **Region 1:** Output pulled hard to VDD.
- **Region 2:** Both transistors in saturation (shortly) causing steep drop. Gain is very high.
- **Region 3:** Output pulled hard to GND.

**Key Features:**

- **Zero Static Power:** In steady states (high/low), one transistor is always OFF.
- **Rail-to-Rail Swing:** Logic levels are exact VDD and GND.
- **Symmetric Design:** If  $\beta_n = \beta_p$ , switching threshold  $V_M = V_{DD}/2$ .

**Mnemonic**

“CMOS has Zero Static Power with Full Swing”

**Question 3(a) [3 marks]**

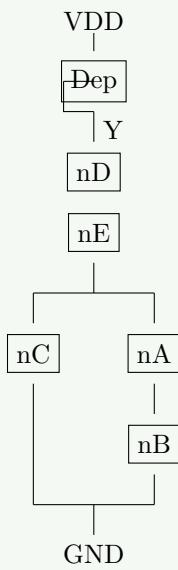
Realize  $Y = (\bar{A} + \bar{B})\bar{C} + \bar{D} + \bar{E}$  using depletion load.

**Solution**

**Logic Simplification:**  $Y = (\bar{A} + \bar{B})\bar{C} + \bar{D} + \bar{E}$ . Wait, let's check exact expression:  $Y = (\bar{A} + \bar{B})\bar{C} + \bar{D} + \bar{E}$ . This looks like sum of products. Depletion load implies NMOS logic. Y is the output of proper logic. Usually we implement the complement in Pull Down. Complement of Y? If Y is the target, and we use NMOS with Depletion load (which is basically an inverter structure for the logic block), the Pull Down network should minimize  $\bar{Y}$ .  $\bar{Y} = (\bar{A} + \bar{B})\bar{C} + \bar{D} + \bar{E} = (\bar{A} + \bar{B})\bar{C} \cdot \bar{D} \cdot \bar{E}$ .  $\bar{Y} = (\bar{A} + \bar{B})\bar{C} \cdot D \cdot E = (\bar{A} + \bar{B} + \bar{C}) \cdot D \cdot E = (AB + C)DE = ABDE + CDE$ .

This seems complex. Let's assume the question implies implementing the function directly as written using "Depletion Load NMOS Logic". Standard NMOS logic implements NOR/NAND inherently. Output  $F = \overline{PDN}$ . So if we want Output Y, we need PDN function equal to  $\bar{Y}$ . Let's re-read: "Realize Y=...". Usually implies: Design a gate where Output is Y. So PDN must implement  $\bar{Y}$ . If  $\bar{Y} = ABDE + CDE = (AB + C)DE$ . PDN: D and E in series with (C parallel (A series B)).

**Depletion Load Implementation:**

**Figure 10.** Depletion Load Logic for Y**Mnemonic**

“Depletion Load with Parallel/Series pull-down Paths”

**Question 3(b) [4 marks]**

**Write a short note on FPGA.**

**Solution**

**FPGA Definition: Field Programmable Gate Array** - A reconfigurable integrated circuit that can be programmed by the customer after manufacturing.

**Architecture Components:**

- **CLB (Configurable Logic Block)**: Basic logic unit (LUTs, Flip-flops).
- **IOB (Input/Output Block)**: Interface with external pins.
- **Interconnects**: Programmable routing channels (Vertical/Horizontal).
- **Switch Matrix**: Programmable connections between routing tracks.

**Programming Technologies:**

- **SRAM-based**: Volatile, fast reconfiguration, high density.
- **Antifuse**: Non-volatile, one-time programmable, secure.
- **Flash-based**: Non-volatile, reprogrammable.

**Advantages vs ASIC:**

- **Flexibility**: Can be updated/fixed post-deployment.
- **Time-to-market**: No physical fabrication wait time.
- **Cost**: Low NRE (Non-Recurring Engineering) cost, good for low volume.

**Mnemonic**

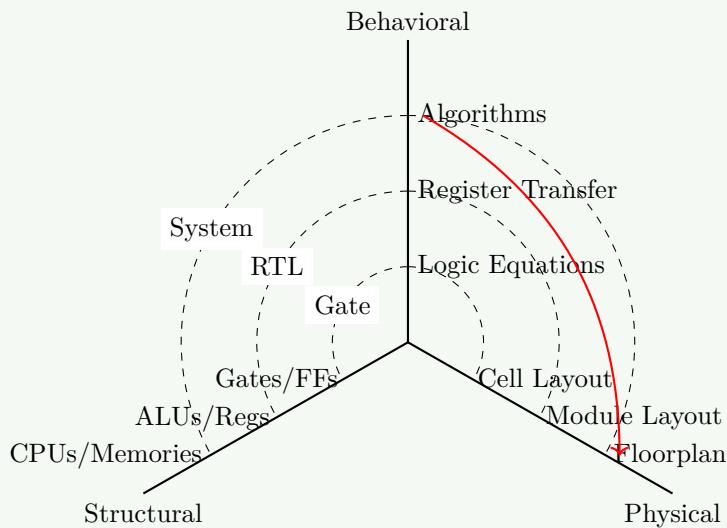
“FPGA - Flexible Programming Gives Advantages”

**Question 3(c) [7 marks]**

**Draw and explain Y chart design flow.**

## Solution

**Y-Chart Diagram:**



**Figure 11.** Gajski-Kuhn Y-Chart

### Design Domains:

- **Behavioral:** Describes *what* simple system does (Algorithms, Equations).
- **Structural:** Describes *how* components are connected (Netlists, Gates).
- **Physical:** Describes *where* components are placed (Layout, Geometry).

### Abstraction Levels:

- **System Level:** High level architectural blocks.
- **RTL:** Data flow between registers.
- **Gate Level:** Boolean logic implementation.
- **Transistor/Layout Level:** Physical device details.

## Mnemonic

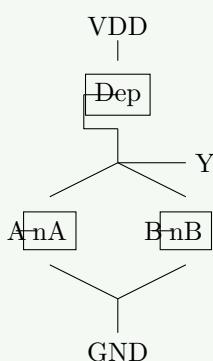
“Y-Chart: Behavioral, Structural, Physical - BSP domains”

## Question 3(a) OR [3 marks]

Explain NOR2 gate using depletion load.

## Solution

**Depletion Load NOR2 Circuit:**



**Figure 12.** Depletion Load NOR2**Operation:**

- Both inputs Low (0,0): Both pull-down NMOS OFF. Output pulled High to VDD by Depletion load.
- Any input High: Corresponding Pull-Down NMOS is ON. Output pulled Low to GND (ratioed logic).

**Mnemonic**

“NOR with Depletion - Parallel NMOS pull-down”

**Question 3(b) OR [4 marks]**

Compare full custom and semi-custom design styles.

**Solution****Comparison Table:**

Parameter	Full Custom	Semi-Custom
<b>Design Time</b>	Long (6-18 months)	Short (2-6 months)
<b>Performance</b>	Optimal	Good
<b>Area</b>	Minimum	Moderate
<b>Power</b>	Optimized	Acceptable
<b>Cost</b>	High NRE	Lower NRE
<b>Flexibility</b>	Maximum	Limited
<b>Risk</b>	High	Lower

**Full Custom Characteristics:**

- Every transistor: Manually designed and placed.
- Layout optimization: Maximum density achieved.
- Applications: High-volume, performance-critical (e.g., Microprocessors).

**Semi-Custom Types:**

- Gate Array: Pre-defined transistor array.
- Standard Cell: Library of pre-designed cells.
- FPGA: Field programmable logic.

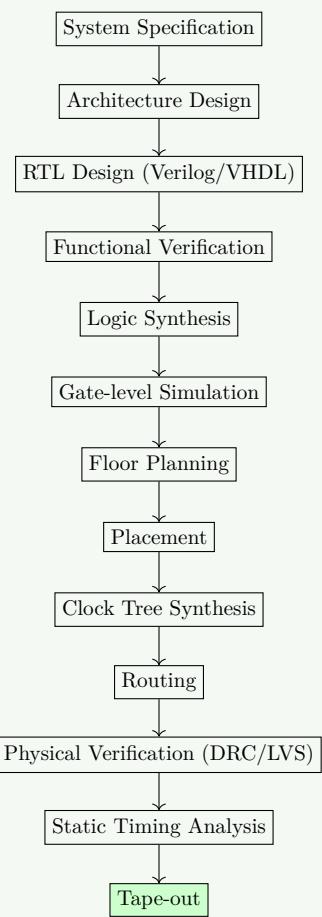
**Mnemonic**

“Full Custom - Maximum control, Semi-Custom - Speed compromise”

**Question 3(c) OR [7 marks]**

Draw and explain ASIC design flow in detail.

**Solution****ASIC Design Flow:**

**Figure 13.** ASIC Design Flow**Design Stages:**

- **RTL Design:** Describing hardware behavior using HDL.
- **Synthesis:** Converting RTL to gate-level netlist.
- **Physical Design:** Floorplanning, Placement, and Routing (P&R).
- **Verification:** ensuring functionality (Functional) and manufacturability (Physical/Timing).

**Mnemonic**

“ASIC flow: RTL to GDSII”

**Question 4(a) [3 marks]**

Implement the logic function  $G = \overline{A(D + E)} + BC$  using CMOS

**Solution**

**Logic Analysis:**  $G = \overline{A(D + E)} + BC$ . PDN implements  $A(D + E) + BC$ .

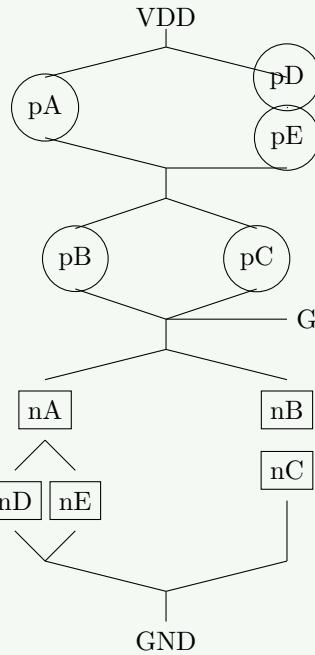
- $D + E \rightarrow D, E$  parallel.
- $A(D + E) \rightarrow A$  in series with ( $D$  parallel  $E$ ).
- $BC \rightarrow B, C$  in series.
- Final OR  $\rightarrow$  The two branches in parallel.

PUN implements dual:

- Dual of  $(D + E)$  is  $D \cdot E$  (series).
- Dual of  $A(\dots)$  is  $A + \dots$  (parallel).

- Dual of  $BC$  is  $B + C$  (parallel).
- Dual of major OR is AND (series).
- So: ( $A$  parallel ( $D$  series  $E$ )) series ( $B$  parallel  $C$ ).

**CMOS Implementation:**



**Figure 14.** Complex CMOS Gate

### Mnemonic

“Complex CMOS - PMOS series, NMOS parallel”

## Question 4(b) [4 marks]

Write a Verilog code for 3 bit parity checker.

### Solution

```

1 module parity_checker_3bit(
2     input [2:0] data_in,
3     output parity_even,
4     output parity_odd
5 );
6
7 // Even parity checker
8 assign parity_even = ~data_in;
9
10 // Odd parity checker
11 assign parity_odd = ~(~data_in);
12
13 endmodule

```

**Truth Table:**

Input [2:0]	# of 1s	Even Parity	Odd Parity
000	0	0	1
001	1	1	0
111	3	1	0

### Question 4(c) [7 marks]

Implement: 1)  $G = (AD + BC + EF)$  using CMOS [3 marks] 2)  $Y' = (ABCD + EF(G + H) + J)$  using CMOS [4 marks]

#### Solution

**Part 1:**  $G = (AD + BC + EF)$  [3 marks]

**CMOS Circuit Analysis:**  $G = (AD + BC + EF)$ . This is a non-inverting function. Using strict static CMOS, we implement  $\overline{G} = \overline{AD + BC + EF}$  and add an inverter. PDN for  $\overline{G}$  matches the function directly (Parallel branches of Series pairs).

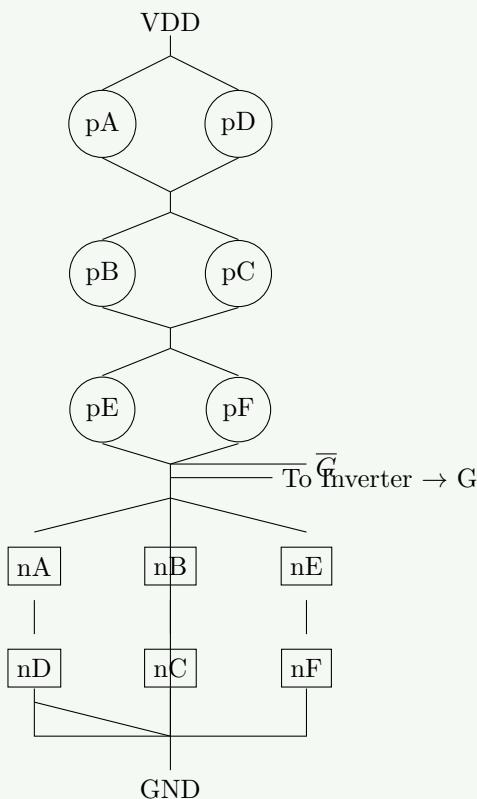


Figure 15. CMOS Logic for  $G$  (Output  $\overline{G}$ )

**Part 2:**  $Y' = (ABCD + EF(G + H) + J)$  [4 marks] This requires a complex single stage. PDN Implementation:

- $ABCD$ : 4 NMOS in series.
- $EF(G + H)$ : G parallel H, series with E and F.
- $J$ : Parallel to everything.
- All combined in parallel structure.

### Question 4(a) OR [3 marks]

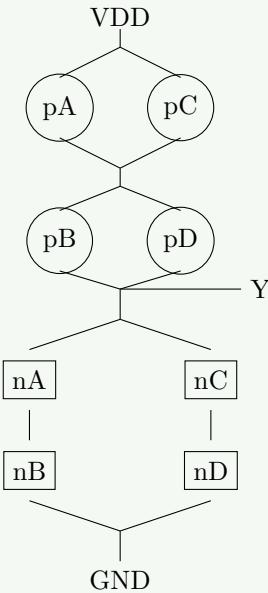
Explain AOI logic with example.

### Solution

**AOI Definition:** AND-OR-Invert logic implements functions of form:  $Y = \overline{(AB + CD + \dots)}$

**Example:**  $Y = \overline{(AB + CD)}$

**AOI Implementation:**



**Figure 16.** AOI Gate Implementation

**Advantages:**

- **Single stage:** Direct implementation.
- **Fast:** No propagation through multiple levels.
- **Area efficient:** Fewer transistors than separate gates.

### Mnemonic

“AOI - AND-OR-Invert in one stage”

## Question 4(b) OR [4 marks]

Write Verilog Code for 4-bit Serial IN Parallel out shift register.

### Solution

```

1 module sipo_4bit(
2     input clk,
3     input reset,
4     input serial_in,
5     output reg [3:0] parallel_out
6 );
7
8 always @(posedge clk or posedge reset) begin
9     if (reset) begin
10         parallel_out <= 4'b0000;
11     end else begin
12         // Shift left and insert new bit at LSB
13         parallel_out <= {parallel_out[2:0], serial_in};
14     end

```

```

15 end
16
17 endmodule

```

## Question 4(c) OR [7 marks]

Implement clocked NOR2 SR latch and D-latch using CMOS.

### Solution

Clocked NOR2 SR Latch:

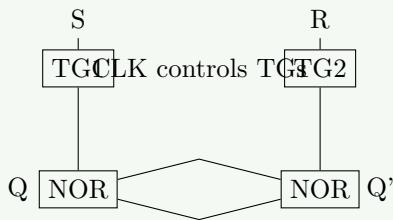


Figure 17. Clocked SR Latch Concept

CMOS D-Latch Circuit:

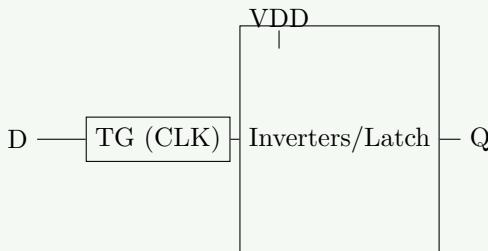


Figure 18. D-Latch

## Question 5(a) [3 marks]

Draw the stick diagram for  $Y = (PQ + U)'$  using CMOS considering Euler path approach.

### Solution

**Logic Analysis:**  $Y = \overline{PQ + U}$ . PDN:  $P \cdot Q + U$  (P series Q, parallel U). PUN:  $\overline{PQ} \cdot \overline{U} = (\bar{P} + \bar{Q}) \cdot \bar{U}$  (P parallel Q, series U).

**Euler Path:** Common sequence: U - P - Q.

**Stick Diagram:**

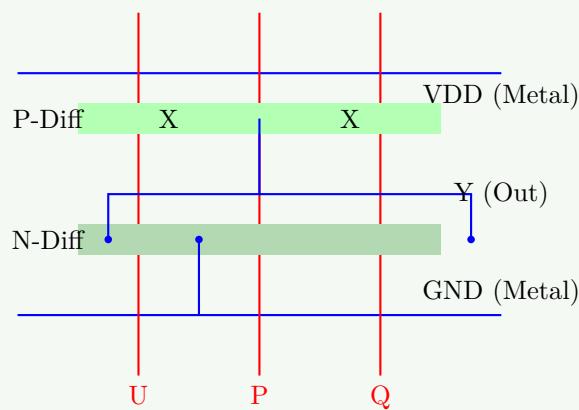


Figure 19. Stick Diagram for Y

**Mnemonic**

“Stick diagram shows physical layout with Euler path optimization”

**Question 5(b) [4 marks]**

Implement 8x1 multiplexer using Verilog.

**Solution**

```

1 module mux_8x1(
2     input [7:0] data_in,
3     input [2:0] select,
4     output reg data_out
5 );
6
7     always @(*) begin
8         case (select)
9             3'b000: data_out = data_in[0];
10            3'b001: data_out = data_in[1];
11            3'b010: data_out = data_in[2];
12            3'b011: data_out = data_in[3];
13            3'b100: data_out = data_in[4];
14            3'b101: data_out = data_in[5];
15            3'b110: data_out = data_in[6];
16            3'b111: data_out = data_in[7];
17             default: data_out = 1'b0;
18         endcase
19     end
20
21 endmodule

```

**Question 5(c) [7 marks]**

Implement full adder using behavioral modeling style in Verilog.

**Solution**

```

1 module full_adder_behavioral(
2     input A,
3     input B,
4     input Cin,
5     output reg Sum,
6     output reg Cout
7 );
8
9 always @(*) begin
10    case ({A, B, Cin})
11        3'b000: begin Sum = 0; Cout = 0; end
12        3'b001: begin Sum = 1; Cout = 0; end
13        3'b010: begin Sum = 1; Cout = 0; end
14        3'b011: begin Sum = 0; Cout = 1; end
15        3'b100: begin Sum = 1; Cout = 0; end
16        3'b101: begin Sum = 0; Cout = 1; end
17        3'b110: begin Sum = 0; Cout = 1; end
18        3'b111: begin Sum = 1; Cout = 1; end
19        default: begin Sum = 0; Cout = 0; end
20    endcase
21 end
22
23 endmodule

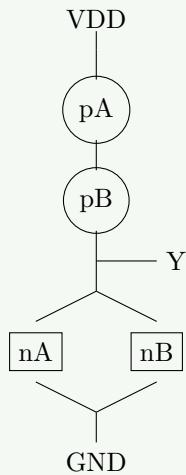
```

**Question 5(a) OR [3 marks]**

Implement NOR2 gate CMOS circuit with its stick diagram.

**Solution**

CMOS NOR2 Circuit:



**Figure 20.** CMOS NOR2 Circuit

Stick Diagram:

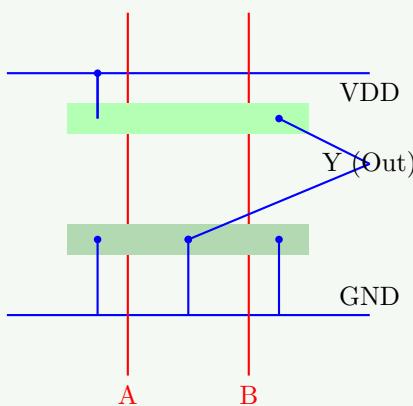


Figure 21. NOR2 Stick Diagram

**Question 5(b) OR [4 marks]**

Implement 4 bit up counter using Verilog

**Solution**

```

1 module counter_4bit_up(
2     input clk,
3     input reset,
4     input enable,
5     output reg [3:0] count
6 );
7
8     always @ (posedge clk or posedge reset) begin
9         if (reset) begin
10             count <= 4'b0000;
11         end else if (enable) begin
12             if (count == 4'b1111) begin
13                 count <= 4'b0000;
14             end else begin
15                 count <= count + 1;
16             end
17         end
18     end
19
20 endmodule

```

**Question 5(c) OR [7 marks]**

Implement 3:8 decoder using behavioral modeling style in Verilog.

**Solution**

```

1 module decoder_3x8_behavioral(
2     input [2:0] address,
3     input enable,
4     output reg [7:0] decode_out
5 );

```

```
6      always @(*) begin
7          if (enable) begin
8              case (address)
9                  3'b000: decode_out = 8'b00000001;
10                 3'b001: decode_out = 8'b00000010;
11                 3'b010: decode_out = 8'b00000100;
12                 3'b011: decode_out = 8'b00001000;
13                 3'b100: decode_out = 8'b00010000;
14                 3'b101: decode_out = 8'b00100000;
15                 3'b110: decode_out = 8'b01000000;
16                 3'b111: decode_out = 8'b10000000;
17             default: decode_out = 8'b00000000;
18         endcase
19     end else begin
20         decode_out = 8'b00000000;
21     end
22 end
23
24 endmodule
```